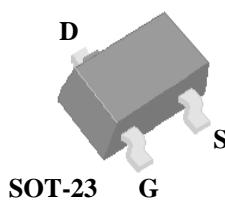


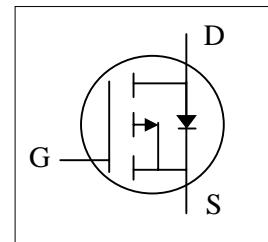
**XP2P038N****Halogen-Free Product**

**P-CHANNEL ENHANCEMENT MODE  
POWER MOSFET**

- ▼ Capable of 1.8V Gate Drive
- ▼ Small Package Outline
- ▼ Surface Mount Device
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	-20V
$R_{DS(ON)}$	38mΩ
$I_D^3$	-5A



## Description

XP2P038 series are innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The SOT-23 package is widely preferred for commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	-20	V
$V_{GS}$	Gate-Source Voltage	+8	V
$I_D @ T_A = 25^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 4.5\text{V}$	-5	A
$I_D @ T_A = 70^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 4.5\text{V}$	-4	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	-20	A
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation	1.38	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-amb}$	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	90	°C/W

**Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=-250\mu\text{A}$	-20	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-4.5\text{V}$ , $I_{\text{D}}=-4\text{A}$	-	-	38	$\text{m}\Omega$
		$V_{\text{GS}}=-2.5\text{V}$ , $I_{\text{D}}=-3\text{A}$	-	-	50	$\text{m}\Omega$
		$V_{\text{GS}}=-1.8\text{V}$ , $I_{\text{D}}=-1\text{A}$	-	-	64	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=-250\mu\text{A}$	-0.3	-	-1	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=-5\text{V}$ , $I_{\text{D}}=-4\text{A}$	-	15	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=-16\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	-10	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 8\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_{\text{g}}$	Total Gate Charge	$I_{\text{D}}=-4\text{A}$	-	14.5	23.2	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=-10\text{V}$	-	3	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	3.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=-10\text{V}$	-	10	-	ns
$t_{\text{r}}$	Rise Time	$I_{\text{D}}=-1\text{A}$	-	17	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	47	-	ns
$t_{\text{f}}$	Fall Time	$V_{\text{GS}}=-5\text{V}$	-	27	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1450	2320	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=-10\text{V}$	-	180	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	135	-	pF

**Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=-1.2\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_{\text{S}}=-4\text{A}$ , $V_{\text{GS}}=0\text{V}$ , $dI/dt=100\text{A}/\mu\text{s}$	-	11	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		-	4	-	nC

**Notes:**

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board,  $t \leq 10\text{s}$  ;  $270^\circ\text{C}/\text{W}$  when mounted on min. copper pad.

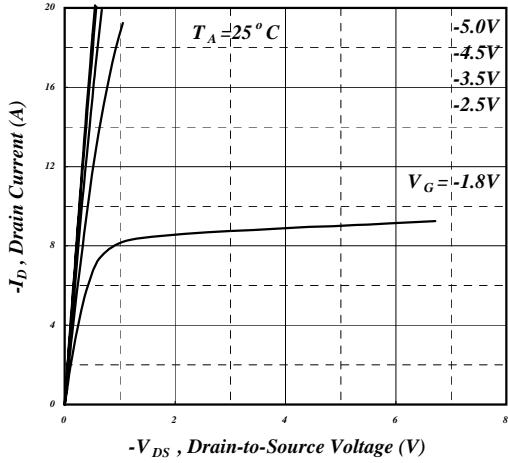
THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT, AUTOMOTIVE OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

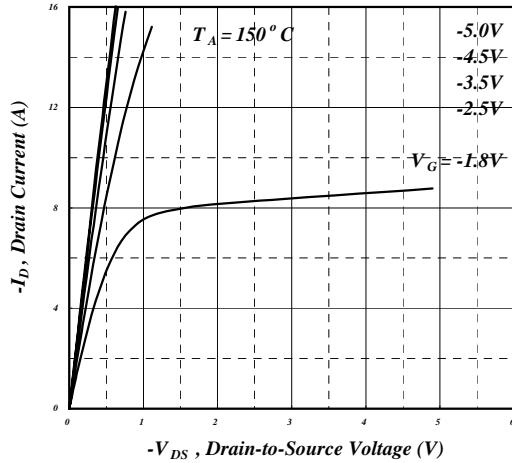
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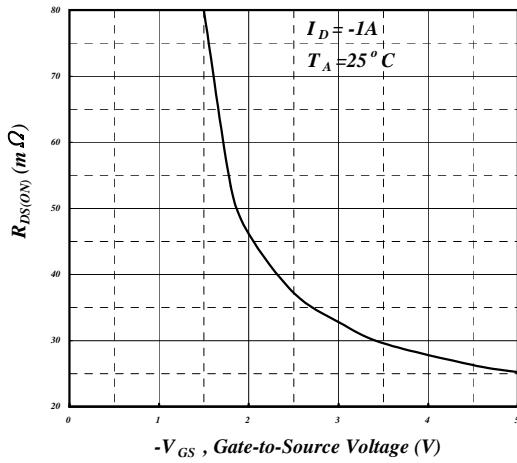
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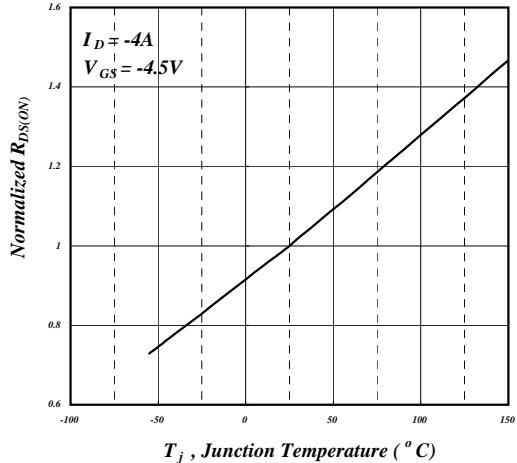
**Fig 1. Typical Output Characteristics**



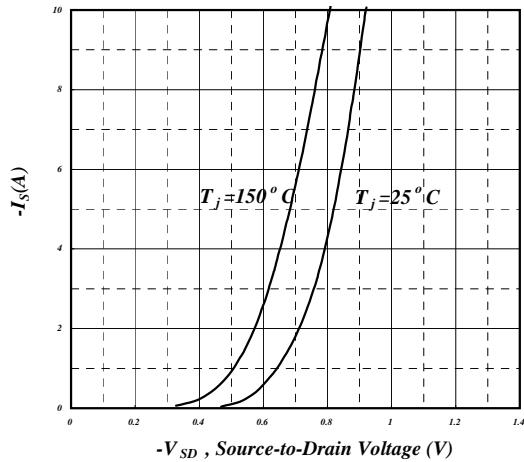
**Fig 2. Typical Output Characteristics**



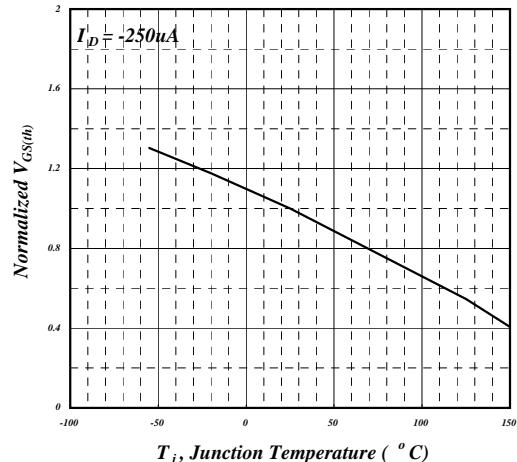
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristic of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

